

Notice of References Cited	Application/Control No. 10/589,837		Applicant(s)/Patent Under Reexamination BEUN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,644,354 A	07-1997	Thompson et al.	725/138
*	B	US-6,035,038 A	03-2000	Campinos et al.	380/228
*	C	US-6,199,762 B1	03-2001	Hohle, William	235/492
*	D	US-6,314,409 B1	11-2001	Schneck et al.	705/54
*	E	US-6,405,369 B1	06-2002	Tsuria, Yossef	725/6
*	F	US-2003/0110382 A1	06-2003	Leporini et al.	713/172
*	G	US-2003/0154375 A1	08-2003	Yang, Weimin	713/172
*	H	US-2003/0188164 A1	10-2003	Okimoto et al.	713/172
*	I	US-2003/0204743 A1	10-2003	Devadas et al.	713/200
*	J	US-2004/0086127 A1	05-2004	Candellere, Brant L.	380/281
*	K	US-2005/0138387 A1	06-2005	Lam et al.	713/185
*	L	US-7,334,735 B1	02-2008	Antebi et al.	235/492
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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